S5 Table. X-ray data collection and refinement statistics.

| Data collection | RM20F (PDB:6VSR) | RM20J (PDB:6VOS) | RM20E1 (PDB:6VOR) |
|--|--|-----------------------------------|---|
| Beamline | SSRL 12-2 | APS 23ID-B | SSRL 12-2 |
| Wavelength (Å) | 0.97946 | 1.03322 | 0.97946 |
| Space group | P 2 ₁ 2 ₁ 2 ₁ | P 4 ₃ 2 ₁ 2 | P1 |
| Unit cell parameters | a=61.5, b=75.6, c=115.1, α= β=γ=90 | a=b=112.3, c=141.0, α=β=γ=90 | a=57.4, b=57.7, c=92.7, α=98.7, β=94.1, γ=97.8 |
| Resolution (Å) | 36.7-2.20 (2.24-2.20) ^a | 50.0-2.30 (2.34-2.30) a | 50.0-1.85 (1.90-1.85) ^a |
| Unique Reflections | 28,053 (1,364) ^a | 40,057 (1,946) ^a | 142,088 (2,413) a |
| Redundancy | 4.0 (4.0) ^a | 17.5 (11.2) ^a | 2.7 (1.3) ^a |
| Completeness (%) | 98.6 (99.4) ^a | 100 (99.6) a | 85.4 (32.5) a |
| <i o<sub="">I></i> | 7.7 (2.0) ^a | 28.0 (1.0) a | 18.8 (1.2) ^a |
| R _{sym} ^b (%) | 19.7 (83.0) ^a | 12.9 (>100) a | 10.9 (69.1) a |
| R _{pim} ^b (%) | 11.0 (46.4) ^a | 3.0 (50.3) a | 4.9 (51.7) a |
| CC _{1/2} ^c (%) | 83.9 (54.0) ^a | 89.7 (44.1) a | 91.6 (56.0) a |
| | Refi | nement statistics | |
| Reflections (work) | 26,622 | 39,953 | 75,965 |
| Reflections (test) | 1,374 | 1,999 | 3,285 |
| R _{cryst} ^d / R _{free} ^e (%) | 19.7/24.1 | 18.1/21.1 | 22.4/25.2 |
| No. of atoms | | | |
| Protein | 3,328 | 3,604 | 6,731 |
| Water | 288 | 224 | 320 |
| Average <i>B</i> -value (Ų) | | | |
| Protein | 25 | 62 | 39 |
| Water | 34 | 68 | 40 |
| Wilson <i>B</i> -value (Ų) | 21 | 57 | 30 |
| | RMSD | rom ideal geometry | |
| Bond length (Å) | 0.002 | 0.007 | 0.008 |
| Bond angle (°) | 0.55 | 0.95 | 0.99 |
| | Ramach | andran statistics (%) | |
| Favored | 97.5 | 96.1 | 96.3 |
| Outliers | 0.0 | 0.2 | 0.1 |

^a Numbers in parentheses refer to the highest resolution shell.

^b $R_{\text{sym}} = \Sigma_{hkl} \Sigma_i \mid I_{hkl,i} - < I_{hkl} \Sigma_i \mid I_{hkl,i}$ and $R_{pim} = \Sigma_{hkl} \left(1/(n-1) \right)^{1/2} \Sigma_i \mid I_{hkl,i} - < I_{hkl} \Sigma_i \mid I_{hkl,i}$, where $I_{hkl,i}$ is the scaled intensity of the i^{th} measurement of reflection h, k, I, $< I_{hkl} >$ is the average intensity for that reflection, and n is the redundancy.

 $^{^{\}rm c}$ CC_{1/2} = Pearson correlation coefficient between two random half datasets.

 $[^]d$ R_{cryst} = Σ_{hkl} | F_{o} - F_{c} | / Σ_{hkl} | F_{o} | x 100, where F_{o} and F_{c} are the observed and calculated structure factors, respectively.

 $^{{}^{\}rm e}R_{\rm free}$ was calculated as for $R_{\rm cryst}$, but on a test set comprising 5% of the data excluded from refinement.